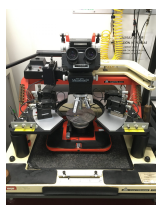


# Semiconductor parameter analyser - Wafer Probe Station

Semiconductor parameter analyser Agilent 4156C, Agilent 41501B ı Wafer Probe Station Karl Suss PSM 6



## Contact information

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## Technological Offers type

Technological scientific services

## Research and innovation areas

- Digital Technologies, Artificial Intelligence, Cybersecurity, 5G, Robotics
- Industry, Materials and Circular Economy
- Science For Engineering and Architecture

## ODS



**Available from:** 2015

### Where?

ISOM Semiconductor Devices Group University Optoelectronics and Microtechnology Systems Institute

Keywords: | DC | Electrical characterization

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## Description of the services offered

Parameter measurement, current-voltage curves and (static)-voltage capacity. 0 V &  $\pm 200$  V,  $\pm 1$  pA &  $\pm 1$  A. 4-position Wafer Probe Station.

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### Needs requested and applications

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### Sector or area of application

Electronics, optoelectronics, quantum communications

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### Differential skills

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### Previous references for provision of services

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### Equipment description

ISOM. HTSE Telecommunications

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## Request for service

[Protocolo de Acceso](#)

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